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Components, Hybrids, and Manufacturing Technology, IEEE Transactions on [see also IEEE Trans. on Components, Packaging, and Manufacturing Technology, Part A, B, C], Volume: 12 Issue: 4, Dec. 1989

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[\[Abstract\]](#) [\[PDF Full-Text \(356 KB\)\]](#) **IEEE JNL****2 Low-frequency measurements and modelling of MLC capacitors***Zhang, T.; Yoo, I.K.; Burton, L.C.;*

Electronic Components Conference, 1989. Proceedings., 39th, 22-24 May 1989

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[\[Abstract\]](#) [\[PDF Full-Text \(332 KB\)\]](#) **IEEE CNF****3 Observation and characterization of near-interface oxide traps with C-V techniques***Cohen, N.L.; Paulsen, R.E.; White, M.H.;*

Electron Devices, IEEE Transactions on, Volume: 42 Issue: 11, Nov. 1995

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[\[Abstract\]](#) [\[PDF Full-Text \(568 KB\)\]](#) **IEEE JNL****4 The dynamic conductance and transconductance in double-gate (gate-all-round) SOI devices**

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1 L-band dielectric resonator filters and oscillators with low vibration sensitivity and ultra low noise

Sparagna, S.M.;

Frequency Control, 1989., Proceedings of the 43rd Annual Symposium on , 31 May-2 June 1989

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[\[Abstract\]](#) [\[PDF Full-Text \(740 KB\)\]](#) **IEEE CNF**

2 Ultra low noise high gain W-band InP-based HEMT downconverter

Chow, P.D.; Tan, K.; Streit, D.; Garske, D.; Liu, P.; Yen, H.C.;

Microwave Symposium Digest, 1991., IEEE MTT-S International , 10-14 June 1991

Page(s): 1041 -1044 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(252 KB\)\]](#) **IEEE CNF**

3 Effects of microcontaminants in oxygen during gate oxide growth: interfacial effects and device reliability

Beck, S.E.; George, M.A.; Bohling, D.A.; Shemanski, B.J.; McGuire, J.T.; Hames, G.A.; Wortman, J.J.; Lanford, W.A.;

Advanced Semiconductor Manufacturing Conference and Workshop. 1994. ASMC 94 Proceedings. IEEE/SEMI , 14-16 Nov. 1994

Page(s): 100 -106

[\[Abstract\]](#) [\[PDF Full-Text \(608 KB\)\]](#) **IEEE CNF**

4 Initial results from the deployment of an ultra-wide band scatterometer

Reed, R.; Long, D.G.; Arnold, D.V.; Collyer, R.S.;

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L2	((438/14 438/17 438/18)!.CCLS.)	1553	L2
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L1	oxide and (semiconductor or silicon) and (interface adj (state or trap)) and (frequency or rate) and gate and drain and source	818	L1

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